ACCEPTANCE AND INSPECTION:

PROCURE ONLY FROM APPROVED SOURCES LISTED IN REQUIREMENTS.

REQUIREMENTS:

1. GENERAL:
   a. INTERPRET DRAWING IN ACCORDANCE WITH STANDARDS PRESCRIBED BY MIL-STD-750.
   b. UNITS SHALL MEET THE REQUIREMENTS OF MIL-STD-19500 WITH THE MODIFICATIONS AND ADDITIONS SPECIFIED HEREIN.
   c. THE SUPPLIER SHALL CONFORM TO THE QUALITY ASSURANCE PROVISIONS AS CONTAINED IN MIL-1015408, CLASS 2.
   d. UNITS SHALL BE COMPLIANT WITH THE QUALIFICATION REQUIREMENTS AS CONTAINED IN NO 1002048 UNLESS MODIFIED OR AMENDED BY SECTION 2 OF THIS DRAWING.
   e. PACKAGING AND PACKING: UNIT PACKAGING AND PACKING SHALL BE IN ACCORDANCE WITH MIL-STD-10491, LEVEL A IN BOTH INSTANCES.

2. ACCEPTANCE AND INSPECTION:
   a. LOT: A LOT IS DEFINED AS A GROUP OF PARTS IN A SINGLE PROCUREMENT SELECTED FROM A SINGLE CONTINUOUS PRODUCTION RUN USING LIKE MATERIALS WHICH ARE CONTROLLED USING A PROCESS WHICH IS THE SAME FROM THE BEGINNING TO THE END OF THE RUN.
   b. INSPECTION CONDITIONS: UNLESS OTHERWISE SPECIFIED HEREIN ALL INSPECTIONS SHALL BE MADE AT AN AMBIENT TEMPERATURE OF PLUS 25 DEGREES CENTIGRADE PLUS 3 DEGREES CENTIGRADE.
   c. ELECTRICAL: 100% TESTING:
      i. UNITS SHALL BE SUBMITTED TO THE ELECTRICAL TESTS SPECIFIED IN NO 1002048.

3. MECHANICAL: (REFERENCE MIL-STD-750 AS MODIFIED HEREIN)
   a. LEAD FATIGUE (DESTRUCTIVE): LEADS SHALL BE FREE FROM KINKS AND NICKS AND SHALL COMPLY WITH THE SPECIFIED LEAD MATERIAL REQUIREMENT. GLASS IN HEADER SHALL HAVE NO CRACKS, CHIPS OR BUBBLES. THIS TEST SHALL BE PERFORMED ON A 100-PERCENT-OF-N-PART BASIS, THIS TEST PERFORMED UNDER 10X MAGNIFICATION
   b. CHASSIS PACKING: EACH CHASSIS SHALL BE CAPABLE OF WITHSTANDING AN AXIAL PULL OF 4 POUNDS MINIMUM FOR 30 SECONDS. NO MECHANICAL DAMAGE SHALL BE VISIBLE AFTER THE TEST. A SAMPLE OF 3 UNITS PER LOT SHALL BE TESTED.
   c. THE ABOVE MECHANICAL TEST TO BE PERFORMED ON ELECTRICAL REJECTS.

PRODUCE ONLY FROM APPROVED SOURCES LISTED IN NO 1002048 FOR THIS DRAWING.
C. THE MANUFACTURER SHALL RECORD THE CHARACTERISTICS LISTED IN TABLE I PRIOR TO AND FOLLOWING HIGH TEMPERATURE STORAGE:

D. UNITS WHICH FAIL TO MEET ALL INITIAL REQUIREMENTS OR WHICH EXCEED THE SPECIFIED LIMITS FOR PARAMETRIC CHANGES FOLLOWING HIGH TEMPERATURE STORAGE SHALL NOT BE SHIPPED.

**TABLE 1**

| ELECTRICAL CHARACTERISTICS AS SPECIFIED IN ACCEPTANCE TEST PROCEDURE NO 1002017 |
|---------------------------------------|---------------------------------------|
| SECTION | PARAMETER | LIMIT |
| 4.8.1.1 | $V_{th}$ | ± 10% |
| 4.8.1.2 | $I_{th}$ | ± 10% |
| 4.8.1.3 | $R_{th}$ | ± 10% |
| 4.7.1.1 | Leakage | ≤ 30% OR LEAKAGE NOT TO EXCEED 75 NANO AMPS |

**TABLE 2**: ALLOWABLE PARAMETER CHANGE LIMITS

1. UNITS SHALL BE STORED FOR 250 HOURS AT 200 DEGREES CENTIGRADE PLUS 10%.
2. UNITS SHALL BE SUBJECTED TO, AND MEET THE REQUIREMENTS OF CONSTANT ACCELERATION TESTS (20,000G) PER MIL-8-19500 METHOD 206.

**NOTICE** — WHEN GOVERNMENT DRAWINGS, SPECIFICATIONS, OR OTHER DATA ARE USED FOR ANY PURPOSE OTHER THAN IN CONNECTION WITH A DEFINITELY RELATED GOVERNMENT PROCUREMENT OPERATION. THE UNITED STATES GOVERNMENT DISCLAIMS ANY RIGHTS OR PERMISSION TO MANUFACTURE, USE, OR SELL ANY PATENTED INVENTION THAT MAY IN ANY WAY BE RELATED THERETO. LICENSING THE HOLDER OR ANY OTHER PERSON OR CORPORATION, OR CONVEYING TO BE IN ANY WAY SUPPLIED THE SAID DRAWINGS, SPECIFICATIONS OR OTHER DATA IS NOT TO BE REGARDED BY IMPLICATION OR OTHERWISE AS IN ANY MANNER TRANSFERRED, LICENSED, OR REVEALED TO THE GOVERNMENT.

**REQUIREMENTS (CONTINUED):**

3. DESIGN:

A. MECHANICAL REQUIREMENTS:


2. MARKING:

(a) UNITS SHALL BE MARKED IN ACCORDANCE WITH ND1002019 C WITH THE MANUFACTURER'S IDENTIFICATION, DATE CODE, SERIAL NUMBER AND THE NUMBER 798 PLUS THE REVISION LETTER A TAG MARKED WITH THE FOREGOING INFORMATION SHALL BE INCLUDED IN EACH CONTAINER.

(b) INTERIOR AND EXTERIOR SHIPPING CONTAINERS SHALL BE MARKED IN ACCORDANCE WITH MIL-STD-129 WITH THE MANUFACTURER'S NAME, LOT OR SERIAL NUMBER, DATE OF MANUFACTURE OR CODING AND THE NASA DRAWING NUMBER AND REVISION LETTER. A TAG MARKED WITH THE FOREGOING INFORMATION SHALL BE INCLUDED IN EACH CONTAINER.

3. ENCLOSURE: METAL CASE WITH GLASS HEADER, HERMETICALLY SEALED SPECIFIED IN ACCEPTANCE TEST PROCEDURE ND1002017.

4. SEMICONDUCTOR MATERIAL: SILICON, NPN, DIFFUSED OXIDE PASSIVATION, SECTION PARAMETER CHANGE LIMIT

5. INTERCONNECTIONS: THE DIFFUSED TRANSISTORS AND RESISTORS SHALL BE INTERCONNECTED AS SHOWN IN FIGURE 1.

THE TRANSISTORS SHALL BE SEPARATED FROM EACH OTHER AND FROM RESISTORS BY DIFFUSED ISOLATION REGIONS.